

Notice of References Cited		Application/Control No. 10/657,097	Applicant(s)/Patent Under Reexamination TANAKA, HIDEO	
		Examiner Allen H. Nguyen	Art Unit 2625	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,952,279	10-2005	Iida, Junichi	358/1.15
*	B	US-6,873,841	03-2005	Sagar, Richard Bryan	455/414.4
*	C	US-2003/0081234	05-2003	Wiley, Jeffrey G.	358/1.13
*	D	US-6,617,969	09-2003	Tu et al.	340/517
*	E	US-2001/0054152	12-2001	Nakao et al.	713/182
*	F	US-2002/0171681	11-2002	Nomura et al.	345/772
*	G	US-6,700,674	03-2004	Otsuka et al.	358/1.15
*	H	US-6,230,189	05-2001	Sato et al.	709/206
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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